



## AO4714

### N-Channel Enhancement Mode Field Effect Transistor **SRFET™**

#### General Description

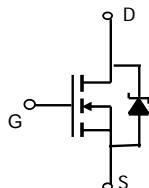
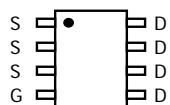
**SRFET™** AO4714 uses advanced trench technology with a monolithically integrated Schottky diode to provide excellent  $R_{DS(ON)}$  and low gate charge. This device is suitable for use as a low side FET in SMPS, load switching and general purpose applications. Standard Product AO4714 is Pb-free (meets ROHS & Sony 259 specifications).

#### Features

$V_{DS}$  (V) = 30V  
 $I_D$  = 20A ( $V_{GS}$  = 10V)  
 $R_{DS(ON)} < 4.7\text{m}\Omega$  ( $V_{GS}$  = 10V)  
 $R_{DS(ON)} < 6.7\text{m}\Omega$  ( $V_{GS}$  = 4.5V)

**UIS TESTED!**

$R_g, C_{iss}, C_{oss}, C_{rss}$  Tested



**SRFET™**  
Soft Recovery MOSFET:  
Integrated Schottky Diode

#### Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	$V_{DS}$	30	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current <sup>F</sup>	$I_{DSM}$	20	A
$T_A=70^\circ\text{C}$		16	
Pulsed Drain Current <sup>B</sup>	$I_{DM}$	100	A
Power Dissipation <sup>F</sup>	$P_{DSM}$	3.0	W
$T_A=70^\circ\text{C}$		2.0	
Avalanche Current <sup>B</sup>	$I_{AR}$	30	A
Repetitive avalanche energy $L=0.3\text{mH}$ <sup>B</sup>	$E_{AR}$	135	mJ
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	°C

#### Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	$R_{\theta JA}$	31	41	°C/W
Steady-State		59	75	°C/W
Maximum Junction-to-Lead <sup>C</sup>	$R_{\theta JL}$	16	24	°C/W

**Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D=1\text{mA}, V_{GS}=0\text{V}$	30			V
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS}=30\text{V}, V_{GS}=0\text{V}$ $T_J=125^\circ\text{C}$		0.1	20	mA
$I_{\text{GSS}}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 20\text{V}$		0.1		$\mu\text{A}$
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	1.2	1.5	2.2	V
$I_{\text{D(ON)}}$	On state drain current	$V_{GS}=10\text{V}, V_{DS}=5\text{V}$	100			A
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=20\text{A}$ $T_J=125^\circ\text{C}$	3.9	4.7		$\text{m}\Omega$
		$V_{GS}=4.5\text{V}, I_D=16\text{A}$	5.9	7.3		$\text{m}\Omega$
$g_{\text{FS}}$	Forward Transconductance	$V_{DS}=5\text{V}, I_D=20\text{A}$		90		S
$V_{\text{SD}}$	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.36	0.5	V
$I_S$	Maximum Body-Diode + Schottky Continuous Current			6		A
<b>DYNAMIC PARAMETERS</b>						
$C_{\text{iss}}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=15\text{V}, f=1\text{MHz}$		3760	4512	pF
$C_{\text{oss}}$	Output Capacitance			682		pF
$C_{\text{rss}}$	Reverse Transfer Capacitance			314		pF
$R_g$	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		0.75	1.5	$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, I_D=20\text{A}$		62	74	
$Q_g(4.5\text{V})$	Total Gate Charge			29	35	nC
$Q_{\text{gs}}$	Gate Source Charge			12		nC
$Q_{\text{gd}}$	Gate Drain Charge			12		nC
$t_{\text{D(on)}}$	Turn-On Delay Time	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, R_L=0.75\Omega, R_{\text{GEN}}=3\Omega$		9.5		ns
$t_r$	Turn-On Rise Time			8.5		ns
$t_{\text{D(off)}}$	Turn-Off Delay Time			34		ns
$t_f$	Turn-Off Fall Time			9		ns
$t_{\text{rr}}$	Body Diode Reverse Recovery Time	$I_F=20\text{A}, dI/dt=300\text{A}/\mu\text{s}$		18	27	ns
$Q_{\text{rr}}$	Body Diode Reverse Recovery Charge	$I_F=20\text{A}, dI/dt=300\text{A}/\mu\text{s}$		22		nC

A: The value of  $R_{\theta JA}$  is measured with the device mounted on 1in 2 FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The value in any given application depends on the user's specific board design.

B: Repetitive rating, pulse width limited by junction temperature  $T_{J(\text{MAX})}=150^\circ\text{C}$ .

C. The  $R_{\theta JA}$  is the sum of the thermal impedance from junction to lead  $R_{\theta JL}$  and lead to ambient.

D. The static characteristics in Figures 1 to 6 are obtained using  $<300\mu\text{s}$  pulses, duty cycle 0.5% max.

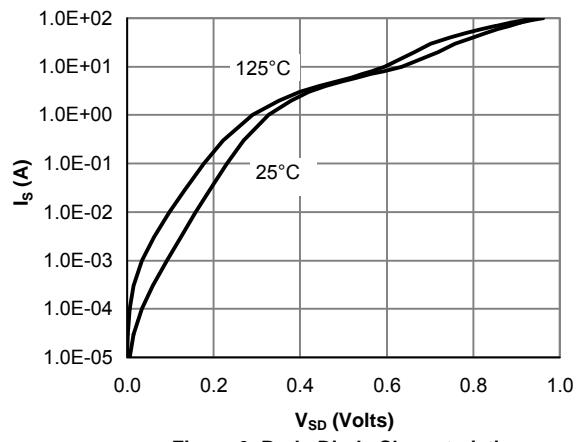
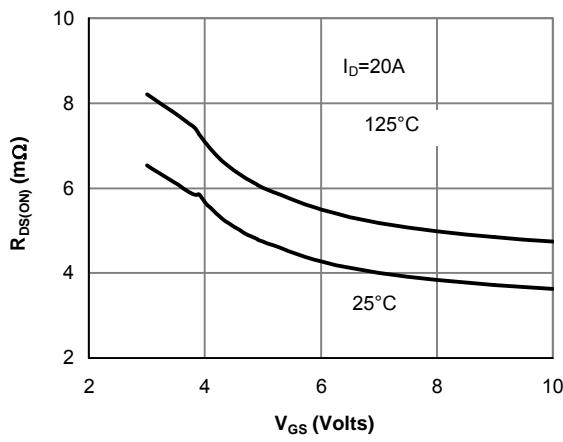
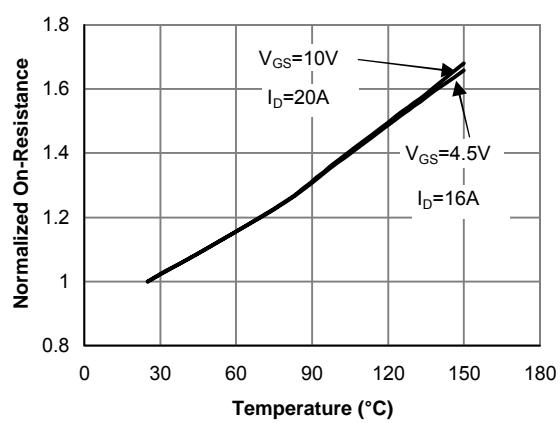
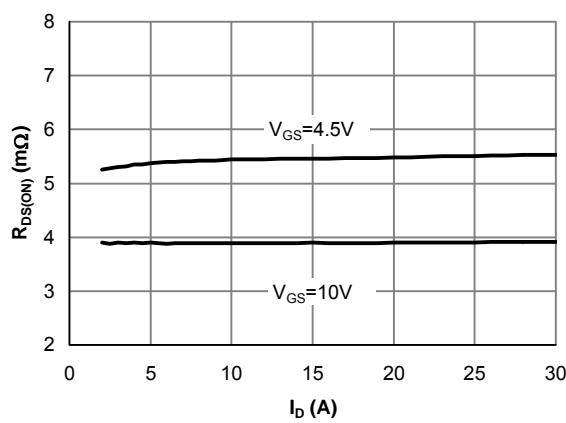
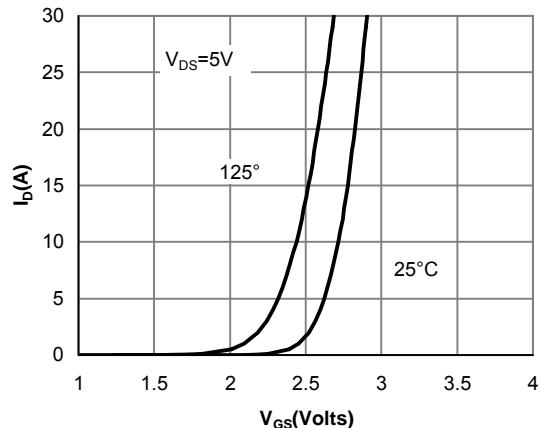
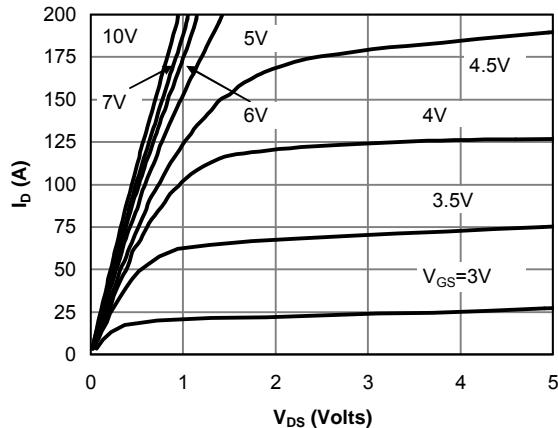
E. These tests are performed with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The SOA curve provides a single pulse rating.

F. The power dissipation and current rating is based on the  $\leq 10\text{s}$  junction to ambient thermal resistance rating.

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## TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



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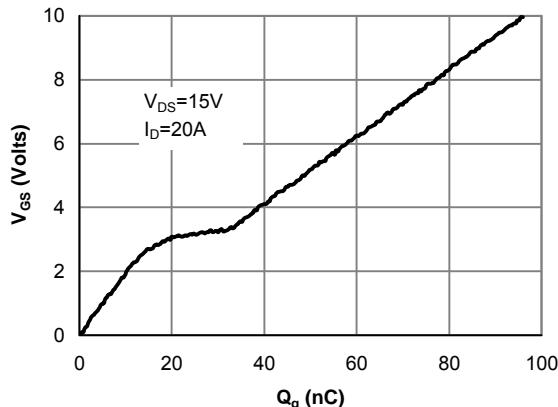


Figure 7: Gate-Charge Characteristics

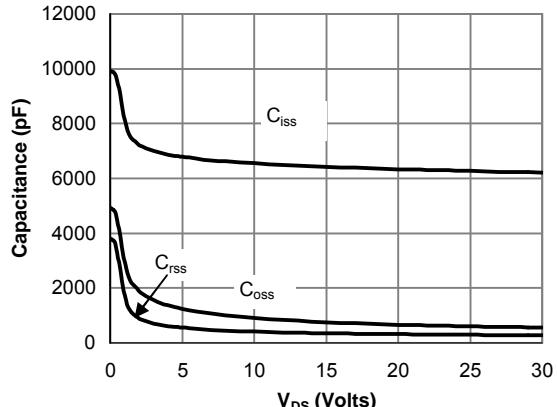


Figure 8: Capacitance Characteristics

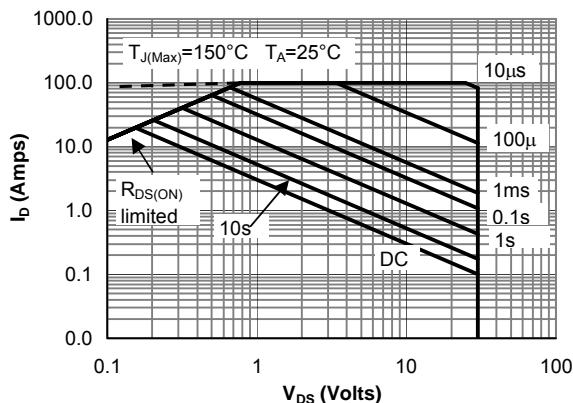


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

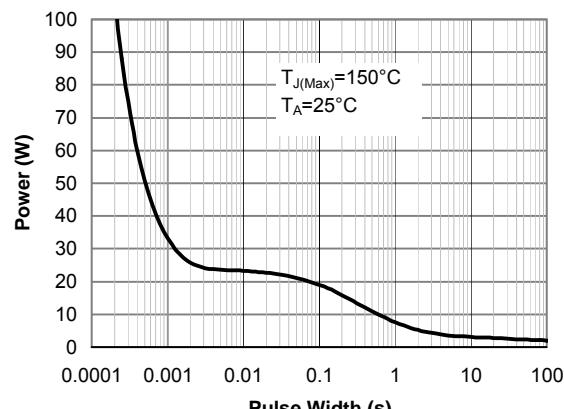


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

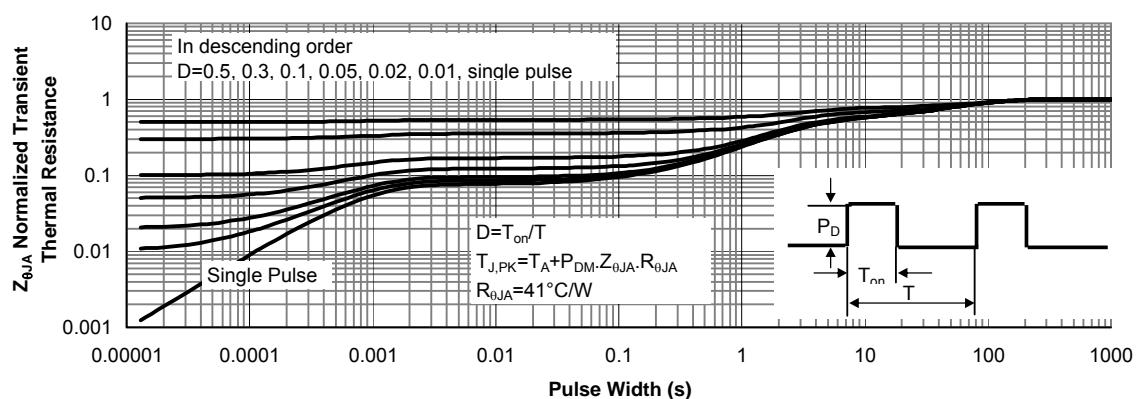


Figure 11: Normalized Maximum Transient Thermal Impedance (Note E)